## Notice of References Cited

	Application/Control No. 10/003,085	Reexaminatio	Applicant(s)/Patent Under Reexamination HAYASHI, KEIICHI		
	Examiner	Art Unit	5 4.54		
1	X L Bautista	2173	Page 1 of 1		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,621,508 B1	09-2003	Shiraishi et al.	345/810
	В	US-6,674,439 B1	01-2004	Shin et al.	345/501
	С	US-6,268,857 B1	07-2001	Fishkin et al.	345/863
	D	US-6,326,985 B1	12-2001	Tazoe et al.	345/764
	E	US-6,507,351 B1	01-2003	Bixler, Donald Brinton	345/810
	F	US-5,796,945	08-1998	Tarabella, Robert M.	709/219
	G	US-5,819,284	10-1998	Farber et al.	709/203
	Н	US-2002/0085024 A1	07-2002	WHITE et al.	345/738
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
1	Р					
	a			•		
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	<b>v</b>	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.